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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Gerhard Kraft and Ulrich Weber

Serial No.: Not Yet Assigned

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Priority Date Claimed: 19 February 1999

For: ION BEAM SCANNER SYSTEM AND OPERATING METHOD

PRELIMINARY AMENDMENT

Box PCT
Commissioner for Patents
Washington, D.C. 20231
Attn: DO/EO/US

S I R:

Preliminary to examination of the above-identified application kindly amend the application as follows:

In the Claims:

Kindly rewrite claims 3-18 and 21-28 as follows:

3. (Amended) Ion beam scanning system according to claim 1, characterized in that the scanning system comprises an electronic control system (14, 34) for the linear drive of the absorber wedges (13) and includes an ionisation chamber (16) for measuring the particle rate of the beam and moves the absorber wedges (13) closer together by a step, preferably of from 10 µm to 100 µm, when a predetermined particle count has been reached, which particle count may be different for each depth step, so

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